

1. Description

The AO6601 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. The complementary MOSFETs form a high-speed power inverter, suitable for a multitude of applications

2.2 Features (P-Ch)

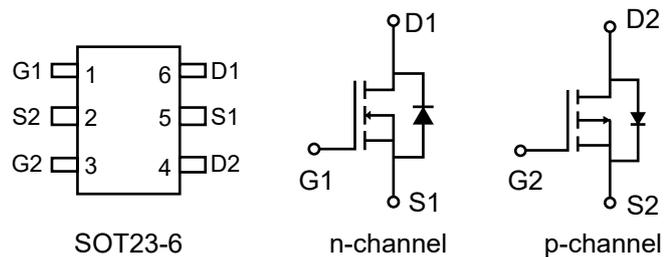
- $V_{DS(V)} = -30V$
- $I_D = -2.3A (V_{GS} = -10V)$
- $R_{DS(ON)} < 115m\Omega (V_{GS} = -10V)$

2.1 Features (N-Ch)

- $V_{DS(V)} = 30V, I_D = 3.4A (V_{GS} = 10V)$
- $R_{DS(ON)} < 60m\Omega (V_{GS} = 10V)$
- $R_{DS(ON)} < 70m\Omega (V_{GS} = 4.5V)$
- $R_{DS(ON)} < 90m\Omega (V_{GS} = 2.5V)$

3. Pinning information

Pin	Symbol	Description
1,3	G1, G2	GATE
5,2	S1, S2	SOURCE
6,4	D1, D2	DRAIN



4. Absolute Maximum Ratings $T_A = 25^\circ C$

Parameter	Symbol	Max n-channel	Max p-channel	Units	
Drain-Source Voltage	V_{DS}	30	-30	V	
Gate-Source Voltage	V_{GS}	± 12	± 12	V	
Continuous Drain Current	I_D	$T_A = 25^\circ C$	3.4	-2.3	A
		$T_A = 70^\circ C$	2.7	-1.8	
Pulsed Drain Current ^C	I_{DM}	20	-15		
Power Dissipation ^B	P_D	$T_A = 25^\circ C$	1.15	1.15	W
		$T_A = 70^\circ C$	0.73	0.73	W
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	-55 to 150	$^\circ C$	



5. Thermal Characteristics

Parameter		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient	$t \leq 10s$	$R_{\theta JA}$	78	110	$^{\circ}C/W$
Maximum Junction-to-Ambient	Steady-State		106	150	$^{\circ}C/W$
Maximum Junction-to-Lead	Steady-State	$R_{\theta JL}$	64	80	$^{\circ}C/W$



6. Electrical Characteristic ($T_J=25^{\circ}\text{C}$ unless otherwise noted)

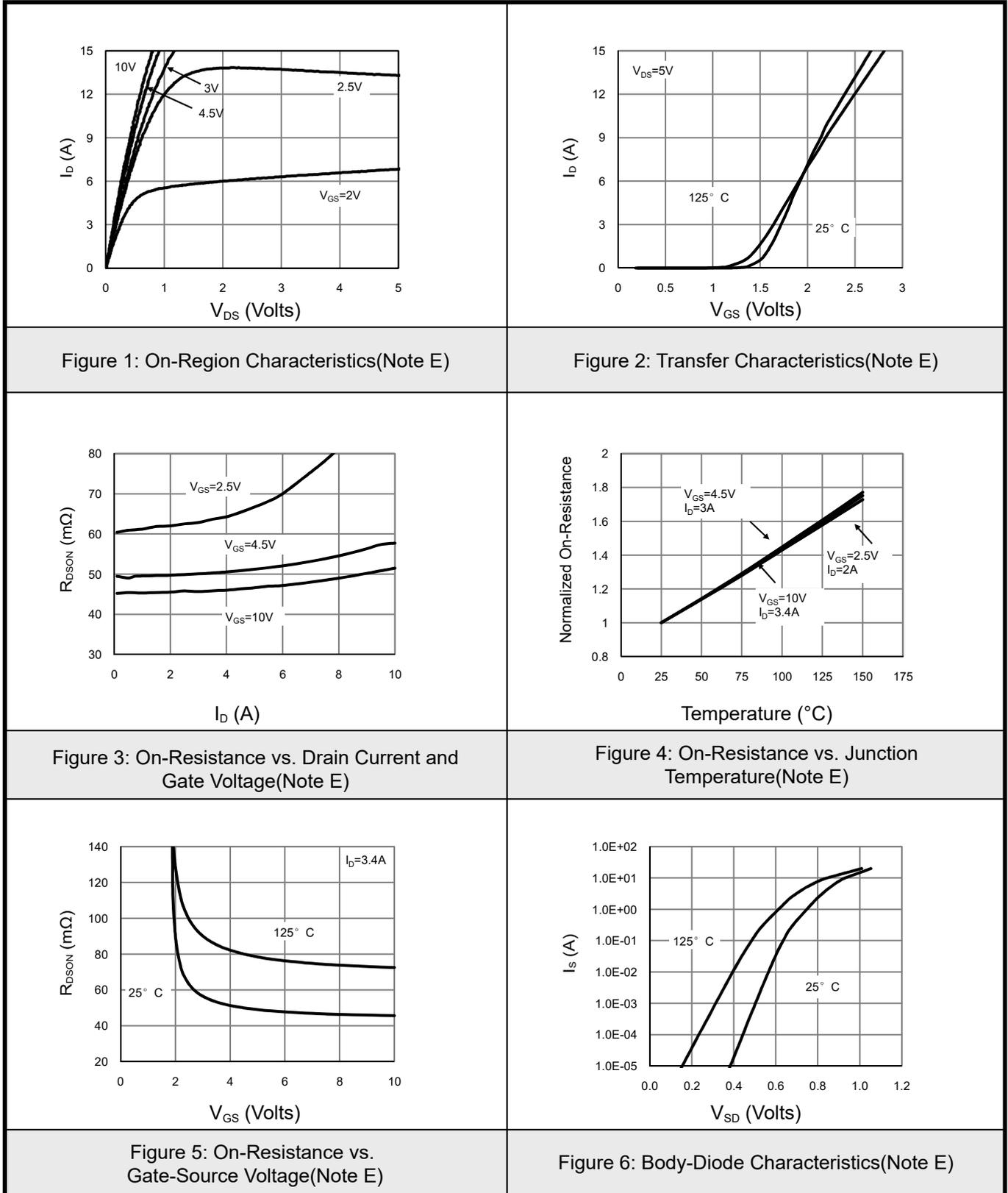
Parameter	Symbol	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D=250\mu\text{A}$, $V_{GS}=0\text{V}$	30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=30\text{V}$, $V_{GS}=0\text{V}$ $T_J=55^{\circ}\text{C}$			1	μA
					5	
Gate-Body leakage current	I_{GSS}	$V_{DS}=0\text{V}$, $V_{GS}=\pm 12\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	0.5	1	1.5	V
On state drain current	$I_{D(ON)}$	$V_{GS}=10\text{V}$, $V_{DS}=5\text{V}$	20			A
Static Drain-Source On-Resistance	$R_{DS(ON)}$	$V_{GS}=10\text{V}$, $I_D=3.4\text{A}$		46	60	m Ω
		$V_{GS}=4.5\text{V}$, $I_D=3\text{A}$		50	70	m Ω
		$V_{GS}=2.5\text{V}$, $I_D=2\text{A}$		62	90	m Ω
Forward Transconductance	g_{FS}	$V_{DS}=5\text{V}$, $I_D=3.4\text{A}$		14		S
Diode Forward Voltage	V_{SD}	$I_S=1\text{A}$, $V_{GS}=0\text{V}$		0.75	1	V
Maximum Body-Diode Continuous Current	I_S				1.5	A
DYNAMIC PARAMETERS						
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}$, $V_{DS}=15\text{V}$, $f=1\text{MHz}$	185	235	285	pF
Output Capacitance	C_{oss}		25	35	45	pF
Reverse Transfer Capacitance	C_{rss}		10	18	25	pF
Gate resistance	R_g	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, $f=1\text{MHz}$	0.9	1.8	2.7	Ω
SWITCHING PARAMETERS						
Total Gate Charge	$Q_g(10\text{V})$	$V_{GS}=10\text{V}$, $V_{DS}=15\text{V}$ $I_D=3.4\text{A}$		10	12	nC
Total Gate Charge	$Q_g(4.5\text{V})$			4.7	6	nC
Gate Source Charge	Q_{gs}			0.95		nC
Gate Drain Charge	Q_{gd}			1.6		nC
Turn-On DelayTime	$t_{D(on)}$	$R_{GEN}=3\Omega$		3.5		ns
Turn-Off DelayTime	$t_{D(off)}$			17.5		ns
Turn-Off Fall Time	t_f			2.5		ns
Body Diode Reverse Recovery Time	t_{rr}	$I_F=3.4\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		8.5	12	ns
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F=3.4\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$		2.55	4	nC



- A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$. The value in any given application depends on the user's specific board design.
- B: The power dissipation P_D is based on $T_{J(\text{MAX})}=150^{\circ}\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.
- C: Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^{\circ}\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^{\circ}\text{C}$.
- D: The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.
- E: The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.
- F: These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^{\circ}\text{C}$. The SOA curve provides a single pulse rating

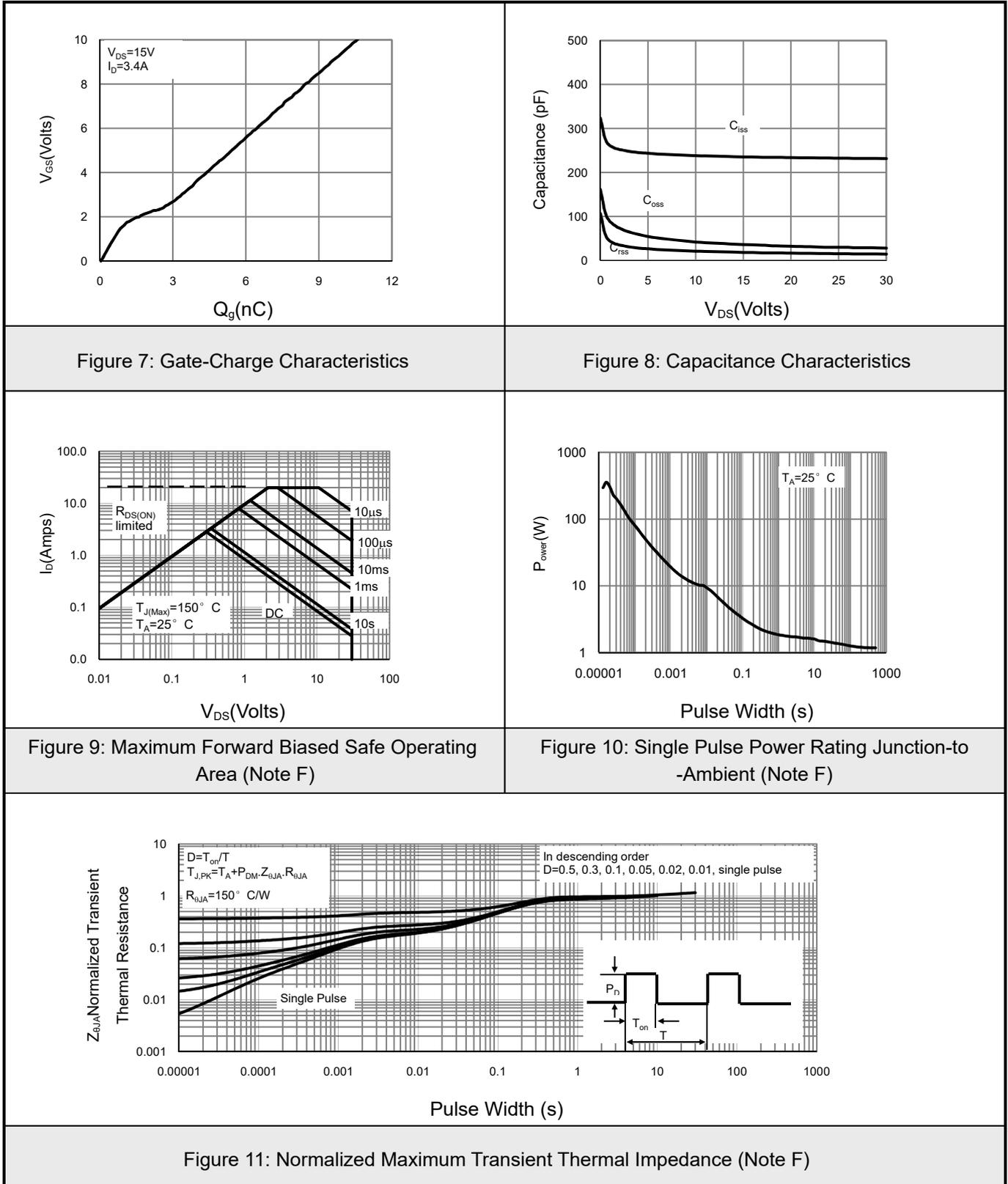


7.1 Typical characteristic





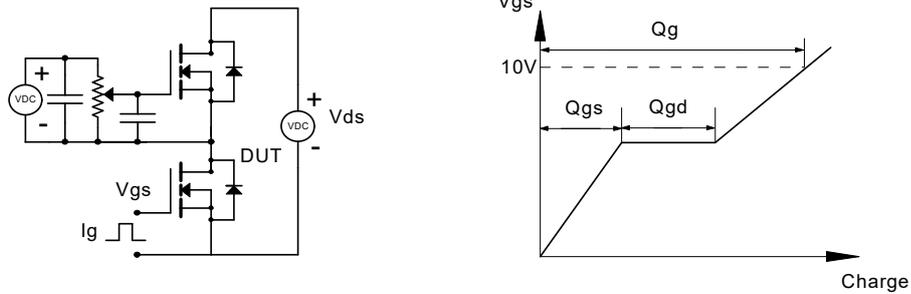
7.2 Typical characteristic



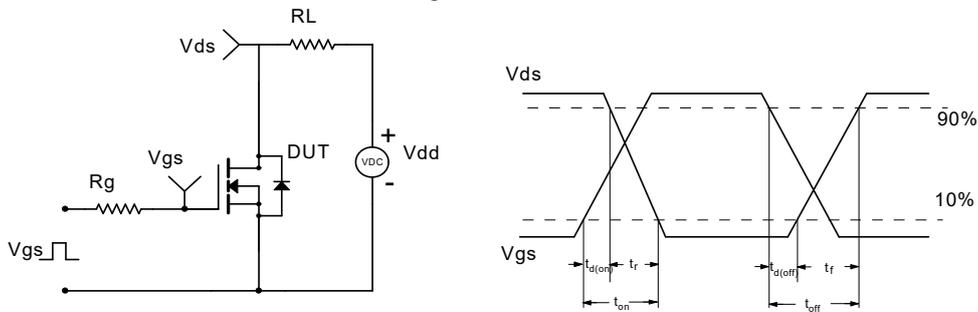


7.3 Typical characteristic

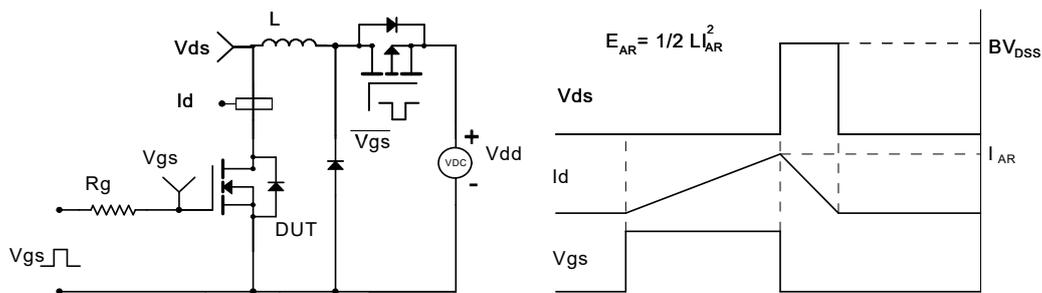
Gate Charge Test Circuit & Waveform



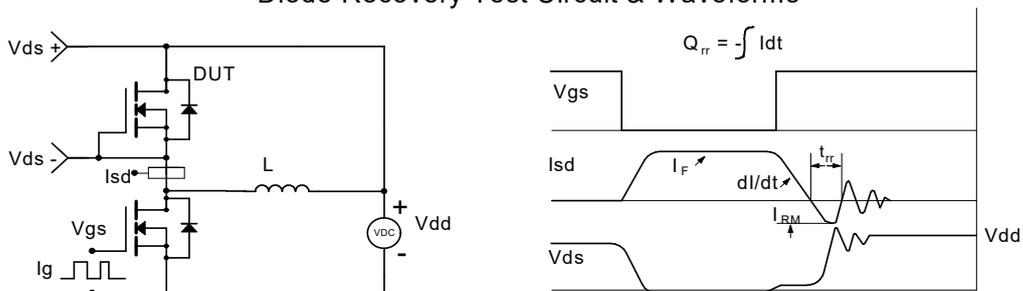
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms





Dual 30V N-Channel MOSFET
Dual -30V P-Channel MOSFET

8. Electrical Characteristic (T_J=25°C unless otherwise noted)

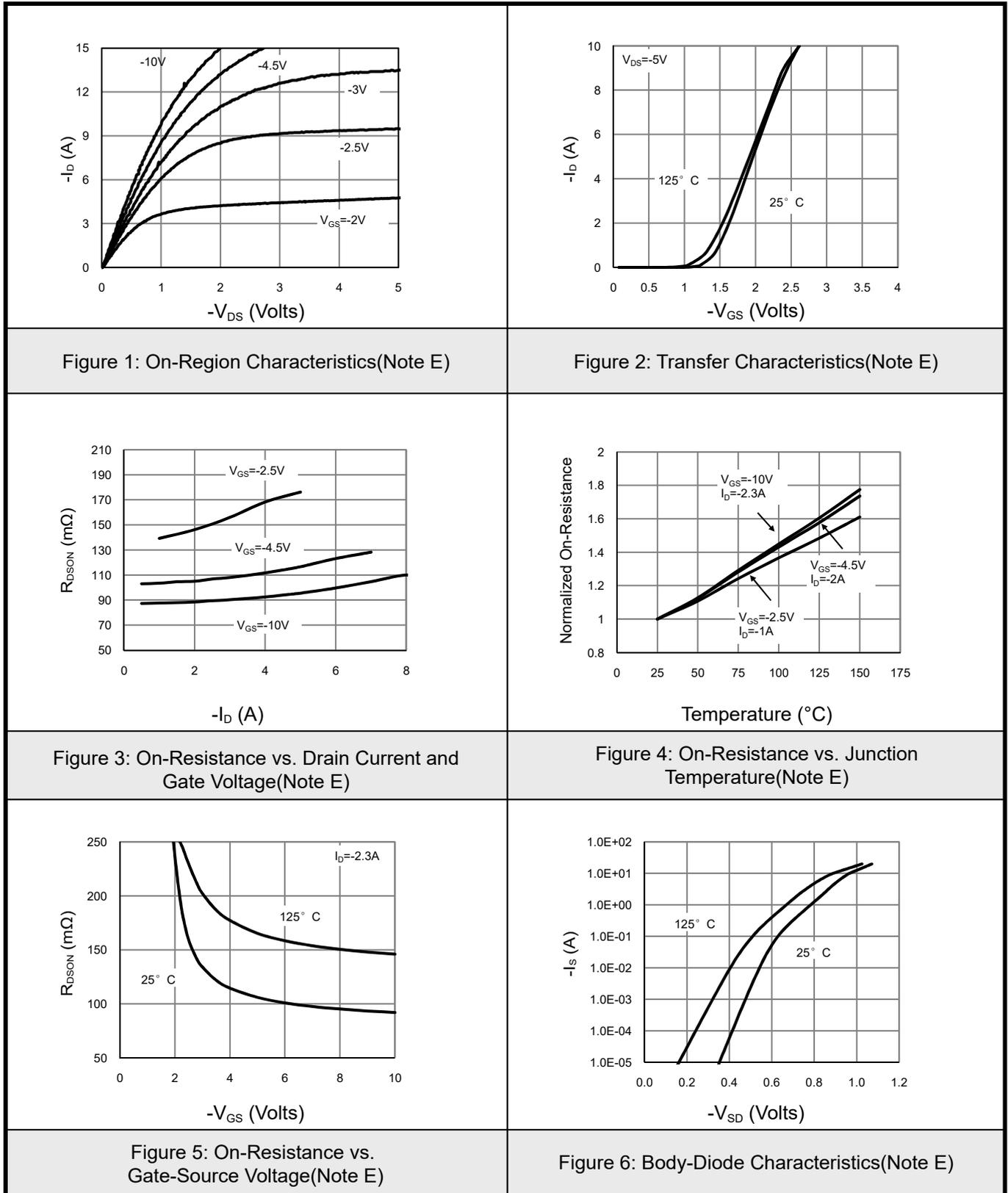
Parameter	Symbol	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =-250μA, V _{GS} =0V	-30			V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-30V, V _{GS} =0V			-1	μA
Gate-Body leakage current	I _{GSS}	V _{DS} =0V, V _{GS} =±12V			±100	nA
Gate Threshold Voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =-250μA	-0.6	-1	-1.4	V
On state drain current	I _{D(ON)}	V _{GS} =-10V, V _{DS} =-5V	-15			A
Static Drain-Source On-Resistance	R _{DS(ON)}	V _{GS} =-10V, I _D =-2.3A		88	115	mΩ
		V _{GS} =-4.5V, I _D =-2A		103	150	mΩ
		V _{GS} =-2.5V, I _D =-1A		139	200	mΩ
Forward Transconductance	g _{FS}	V _{DS} =-5V, I _D =-2.3A		8		S
Diode Forward Voltage	V _{SD}	I _S =-1A, V _{GS} =0V		-0.78	-1	V
Maximum Body-Diode Continuous Current	I _S				-1.5	A
DYNAMIC PARAMETERS						
Input Capacitance	C _{iss}	V _{GS} =0V, V _{DS} =-15V, f=1MHz	205	260	315	pF
Output Capacitance	C _{oss}		25	37	50	pF
Reverse Transfer Capacitance	C _{rss}		10	20	30	pF
Gate resistance	R _g	V _{GS} =0V, V _{DS} =0V, f=1MHz	4	8	12	Ω
SWITCHING PARAMETERS						
Total Gate Charge	Q _{g(10V)}	V _{GS} =10V, V _{DS} =-15V I _D =-2.3A	4.5	5.9	7	nC
Total Gate Charge	Q _{g(4.5V)}		2	2.8	4	nC
Gate Source Charge	Q _{gs}		0.7			nC
Gate Drain Charge	Q _{gd}		1			nC
Turn-On DelayTime	t _{D(on)}	R _{GEN} =3Ω		6		ns
Turn-Off DelayTime	t _{D(off)}			20		ns
Turn-Off Fall Time	t _f			5		ns
Body Diode Reverse Recovery Time	t _{rr}	I _F =-2.3A, dI/dt=100A/μs		11.5	15	ns
Body Diode Reverse Recovery Charge	Q _{rr}	I _F =-2.3A, dI/dt=100A/μs		4.5	6	nC



- A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.
- B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.
- C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.
- D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.
- E. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.
- F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating

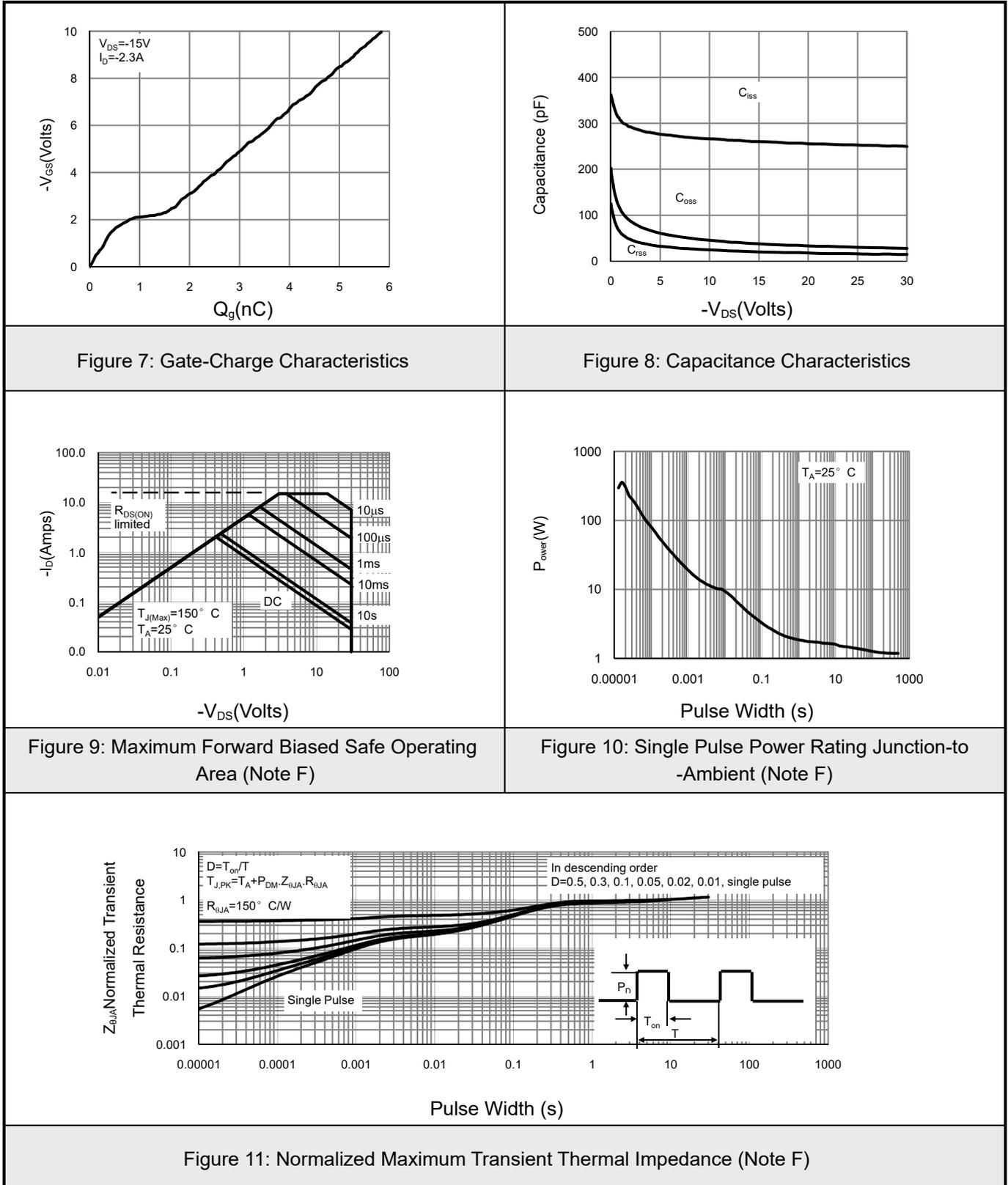


9.1 Typical characteristic





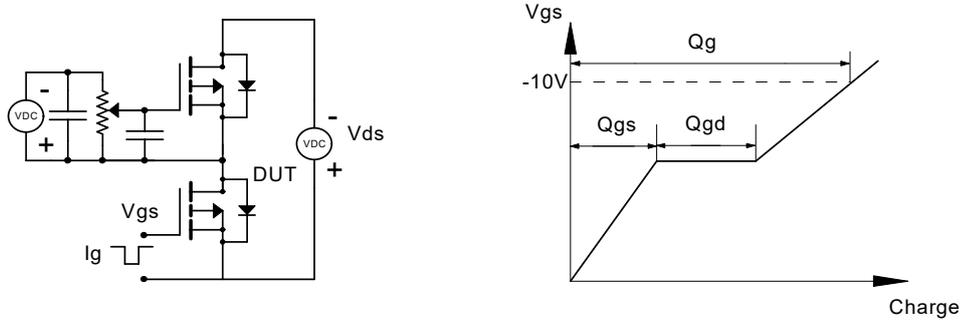
9.2 Typical characteristic



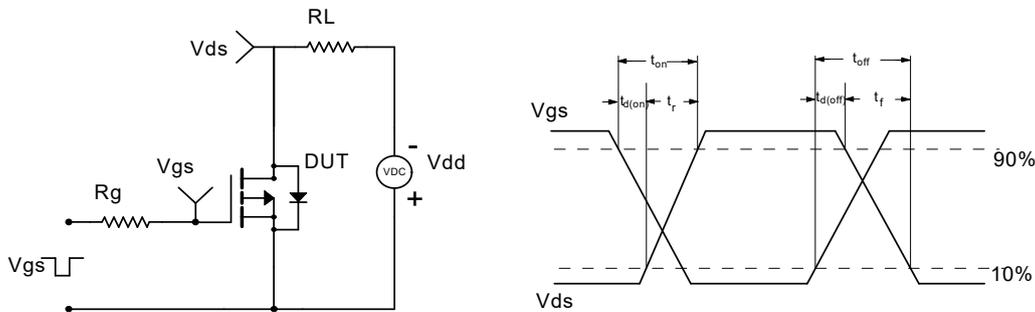


9.3 Typical characteristic

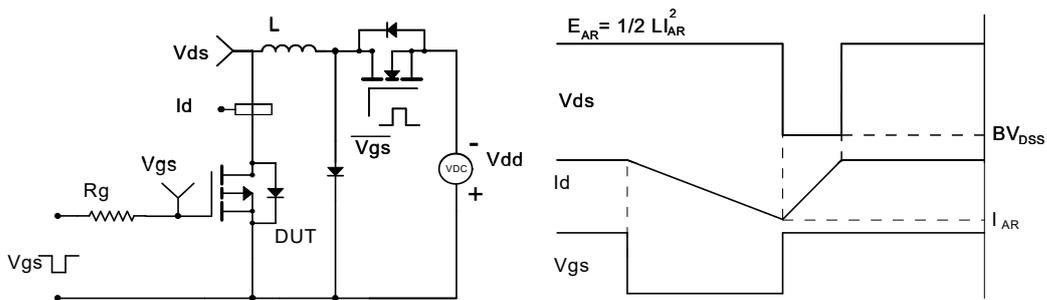
Gate Charge Test Circuit & Waveform



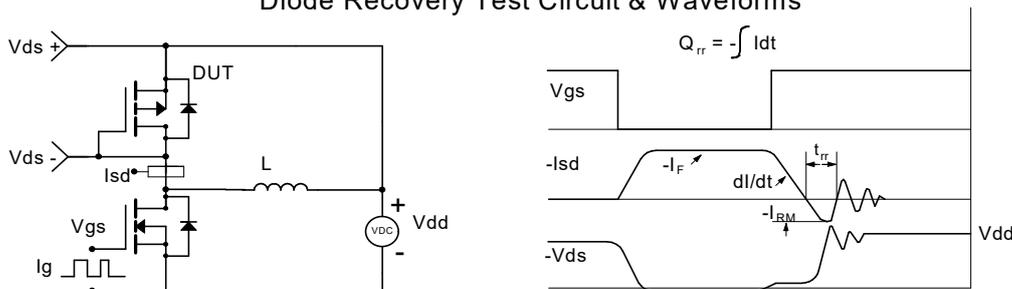
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



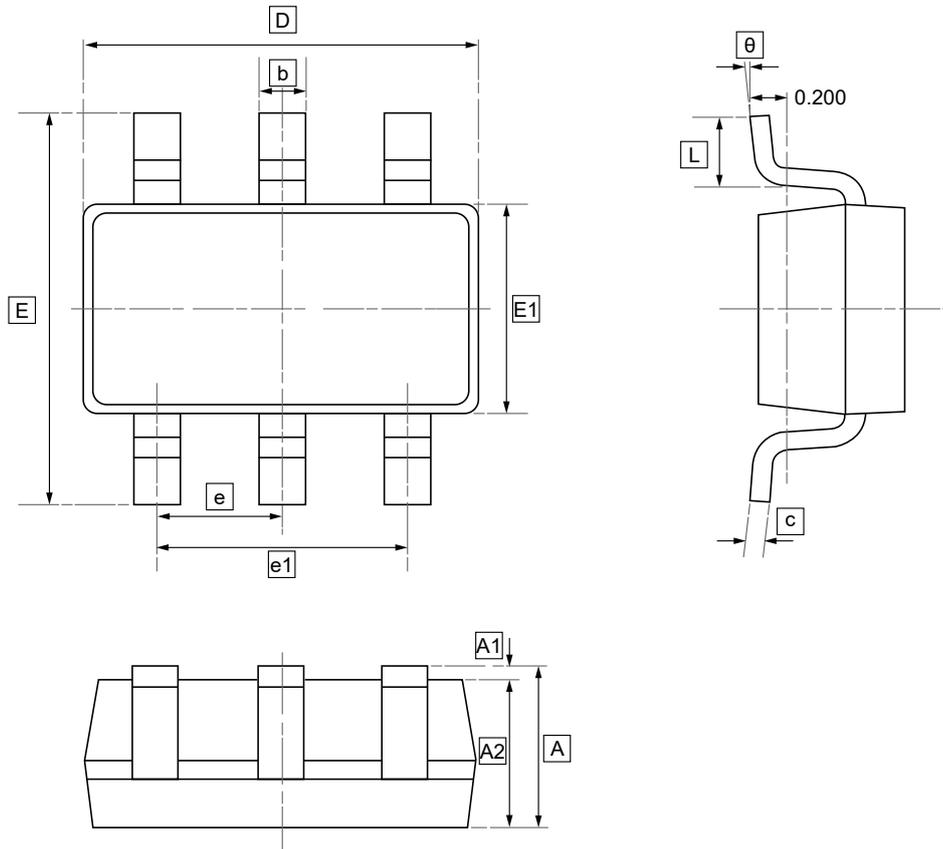
Diode Recovery Test Circuit & Waveforms





Dual 30V N-Channel MOSFET
Dual -30V P-Channel MOSFET

10.SOT23-6 Package Outline Dimensions



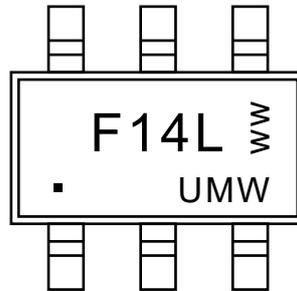
DIMENSIONS (mm are the original dimensions)

Symbol	A	A1	A2	b	c	D	E1	E	e	e1	L	θ
Min	1.050	0.000	1.050	0.300	0.100	2.820	1.500	2.650	0.950	1.800	0.300	0°
Max	1.250	0.100	1.150	0.500	0.200	3.020	1.700	2.950	BSC	2.000	0.600	8°



Dual 30V N-Channel MOSFET
Dual -30V P-Channel MOSFET

11. Ordering information



ww: Week Code

Order Code	Package	Base QTY	Delivery Mode
UMW AO6601	SOT23-6	3000	Tape and reel



12.Disclaimer

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